On a Hypergraph Approach to Multistage Group Testing Problems¹

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Abstract. Group testing is a well known search problem that consists in detecting up to *s* defective elements of the set $[t] = \{1, \ldots, t\}$ by carrying out tests on properly chosen subsets of [t]. In classical group testing the goal is to find all defective elements by using the minimal possible number of tests. In this paper we consider multistage group testing. We propose a general idea how to use a hypergraph approach to searching defects. For the case s = 2, we design an explicit construction, which makes use of $2 \log_2 t(1 + o(1))$ tests in the worst case and consists of 4 stages.

1 Introduction

Group testing is a very natural combinatorial problem that consists in detecting up to s defective elements of the set of objects $[t] = \{1, \ldots, t\}$ by carrying out tests on properly chosen subsets (pools) of [t]. The test outcome is positive if the tested pool contains one or more defective elements; otherwise, it is negative.

There are two general types of algorithms. In *adaptive* group testing, at each step the algorithm decides which group to test by observing the responses of the previous tests. In *non-adaptive* algorithm, all tests are carried out in parallel. There is a compromise algorithm between these two types, which is called a *multistage* algorithm. For the multistage algorithm all tests are divided into p sequential stages. The tests inside the same stage are performed simultaneously. The tests of the next stages may depend on the responses of the previous. In this context, a non-adaptive group testing algorithm is reffered to as a one stage algorithm.

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1.1 Previous results

We refer the reader to the monograph [1] for a survey on group testing and its applications. In spite of the fact that the problem of estimating the minimum *average* (the set of defects is chosen randomly) number of tests has been investigated in many papers (for instance, see [2, 3]), in the given paper we concentrate our attention only on the minimal number of test in the *worst case*.

In 1982 [4], Dyachkov and Rykov proved that at least

$$\frac{s^2}{2\log_2(e(s+1)/2)}\log_2 t(1+o(1))$$

tests are needed for non-adaptive group testing algorithm.

If the number of stages is 2, then it was proved that $O(s \log_2 t)$ tests are already sufficient. It was shown by studying random coding bound for disjunctive list-decoding codes [6, 7] and selectors [8]. The recent work [5] has significantly improved the constant factor in the main term of number of tests for two stage group testing procedures. In particular, if $s \to \infty$, then

$$\frac{se}{\log_2 e}\log_2 t(1+o(1))$$

tests are enough for two stage group testing.

As for adaptive strategies, there exist such ones that attain the information theory lower bound $s \log_2 t(1 + o(1))$. However, for s > 1 the number of stages in well-known optimal strategies is a function of t, and grows to infinity as $t \to \infty$.

1.2 Summary of the results

In the given article we present some explicit algorithms, in which we make a restriction on the number of stages. It will be a function of s. We briefly give necessary notations in section 2. Then, in section 3, we present a general idea of searching defects using a hypergraph approach. In section 4, we describe a 4-stage group testing strategy, which detects 2 defects and uses the asymptotically optimal number of tests $2 \log_2 t(1 + o(1))$. As far as we know the best result for such a problem was obtained [9] by Damashke et al. in 2013. They provide an exact two stage group testing strategy and use $2.5 \log_2 t$ tests. For other constructions for the case of 2 defects, we refer to [10, 11].

2 Preliminaries

Throughout the paper we use t, s, p for the number of elements, defectives, and stages, respectively. Let \triangleq denote the equality by definition, |A| – the

cardinality of the set A. The binary entropy function h(x) is defined as usual

$$h(x) = -x \log_2(x) - (1-x) \log_2(1-x).$$

A binary $(N \times t)$ -matrix with N rows $\boldsymbol{x}_1, \ldots, \boldsymbol{x}_N$ and t columns $\boldsymbol{x}(1), \ldots, \boldsymbol{x}(t)$ (codewords)

 $X = ||x_i(j)||, \quad x_i(j) = 0, 1, \quad i \in [N], \ j \in [t]$

is called a *binary code of length* N and size t. The number of 1's in the codeword x(j), i.e., $|\boldsymbol{x}(j)| \triangleq \sum_{i=1}^{N} x_i(j) = wN$, is called the *weight* of $\boldsymbol{x}(j), j \in [t]$ and parameter w, 0 < w < 1, is the *relative weight*.

One can see that the binary code X can be associated with N tests. A column $\boldsymbol{x}(j)$ corresponds to the *j*-th sample; a row \boldsymbol{x}_i corresponds to the *i*-th test. Let $\mathbf{u} \bigvee \mathbf{v}$ denote the disjunctive sum of binary columns $\mathbf{u}, \mathbf{v} \in \{0, 1\}^N$. For any subset $\mathcal{S} \subset [t]$ define the binary vector

$$r(X, \mathcal{S}) = \bigvee_{j \in \mathcal{S}} \boldsymbol{x}(j),$$

which later will be called the *outcome vector*.

By S_{un} , $|S_{un}| \leq s$, denote an unknown set of defects. Suppose there is a *p*-stage group testing strategy \mathfrak{S} which finds up to *s* defects. It means that for any $S_{un} \subset [t]$, $|S_{un}| \leq s$, according to \mathfrak{S} :

- 1. we are given with a code X_1 assigned for the first stage of group testing;
- 2. we can design a code X_{i+1} for the *i*-th stage of group testing, based on the outcome vectors of the previous stages $r(X_1, \mathcal{S}_{un}), r(X_2, \mathcal{S}_{un}), \ldots, r(X_i, \mathcal{S}_{un});$
- 3. we can identify all defects \mathcal{S}_{un} using $r(X_1, \mathcal{S}_{un}), r(X_2, \mathcal{S}_{un}), \ldots, r(X_p, \mathcal{S}_{un})$.

Let N_i be the number of test used on the *i*-th stage and

$$N_T(\mathfrak{S}) = \sum_{i=1}^p N_i$$

be the maximal total number of tests used for the strategy \mathfrak{S} . We define $N_p(t,s)$ to be the minimal worst-case total number of tests needed for group testing for t elements, up to s defectives, and at most p stages.

3 Hypergraph approach to searching defects

Let us introduce a hypergraph approach to searching defects. Suppose a set of vertices V is associated with the set of samples [t], i.e. $V = \{1, 2..., t\}$.

First stage: Let X_1 be the code corresponding to the first stage of group testing. For the outcome vector $r = r(X_1, S_{un})$ let E(r, s) be the set of subsets of $S \subset V$ of size at most s such that $r(X, S) = r(X, S_{un})$. So, the pair (V, E(r, s))forms the hypergraph $H = H(X_1)$. We will call two vertices *adjacent* if they are included in some hyperedge of H. Suppose there exist a *good* vertex coloring of H in k colours, i.e., assignment of colours to vertices of H such that no two adjacent vertices share the same colour. By $V_i \subset V$, $1 \leq i \leq k$, denote vertices corresponding to the *i*-th colour. One can see that all these sets are pairwise disjoint.

Second stage:

Now we can perform k tests to check which of monochromatic sets V_i contain a defect. Here we find the cardinality of set S_{un} and $|S_{un}|$ sets $\{V_{i_1}, \ldots, V_{i_{|S_{un}|}}\}$, each of which contains exactly one defective element.

Third stage:

Carrying out $\lceil \log_2 |V_{i_1}| \rceil$ tests we can find a vertex v, corresponding to the defect, in the suspicious set V_{i_1} . Observe that actually by performing $\sum_{i=1}^{S_{un}} \lceil \log_2 |V_{i_j}| \rceil$ tests we could identify all defects S_{un} on this stage.

Fourth stage:

Consider all hyperedges $e \in E(r, s)$, such that e contains the found vertex v and consists of vertices of $v \cup V_{i_2} \cup \ldots \cup V_{i_{|S_{un}|}}$. At this stage we know that the unknown set of defects coincides with one of this hyperedges. To check if the hyperedge e is the set of defects we need to test the set $[t] \setminus e$. Hence, the number of test at fourth stage is equal to degree of the vertex v.

4 Optimal searching of 2 defects

Now we consider a specific construction of 4-stage group testing. Then we upper bound number of tests N_i at each stage.

First stage:

Let $C = \{0, 1, \dots, q-1\}^{\hat{N}}$ be the *q*-ary code, consisting of all *q*-ary words of length \hat{N} and having size $t = q^{\hat{N}}$. Let D be the set of all binary words with length N' such that the weight of each codeword is fixed and equals wN', 0 < w < 1, and the size of D is at least q, i.e., $q \leq \binom{N'}{wN'}$. On the first stage we use the concatenated binary code X_1 of length $N_1 = \hat{N} \cdot N'$ and size $t = q^{\hat{N}}$, where the inner code is D, and the outer code is C. We will say X_1 consists of \hat{N} layers. Observe that we can split up the outcome vector $r(X_1, \mathcal{S}_{un})$ into \hat{N} subvectors of lengths N'. So let $r_j(X_1, \mathcal{S}_{un})$ correspond to $r(X_1, \mathcal{S}_{un})$ restricted to the *j*-th layer. Let $w_j, j \in [\hat{N}]$, be the relative weight of $r_j(X_1, \mathcal{S}_{un})$, i.e., $|r_j(X_1, \mathcal{S}_{un})| = w_j N'$ is the weight of the *j*-th subvector of $r(X_1, \mathcal{S}_{un})$.

If $w_j = w$ for all $j \in [\hat{N}]$, then we can say that \mathcal{S}_{un} consists of 1 element and easily find it.

If there are at least two defects, then suppose for simplicity that $S_{un} = \{1, 2\}$. The two corresponding codewords of C are c_1 and c_2 . There exists a coordinate $i, 1 \leq i \leq \hat{N}$, in which they differs, i.e., $c_1(i) \neq c_2(i)$. Notice that the relative weight w_i is bigger than w.

For any $i \in [\hat{N}]$ such that $w_i > w$, we can colour all vertices V in q colours, where the colour of j-th vertex is determined by the corresponding q-nary symbol $c_i(j)$ of code C.

One can check that such a coloring is a good vertex coloring.

Second stage:

We perform q tests to find which coloured group contain 1 defect.

Third stage:

Let us upper bound the size \hat{t} of one of such suspicious group:

$$\hat{t} \leqslant \begin{pmatrix} w_1 N' \\ wN' \end{pmatrix} \cdot \ldots \cdot \begin{pmatrix} w_{\hat{N}} N' \\ wN' \end{pmatrix}.$$

In order to find one defect in the group we may perform $\left[\log_2 \hat{t}\right]$ tests.

Fourth stage:

On the final step, we have to bound the degree of the found vertex $v \in V$ in the graph. The degree deg(v) is bounded as

$$\deg(v) \leqslant \binom{wN'}{(2w - w_1)N'} \cdot \ldots \cdot \binom{wN'}{(2w - w_{\hat{N}})N'}.$$

We know that the second defect corresponds to one of the adjacent to v vertices. Therefore, to identify it we have to make $\lceil \log_2 \deg(v) \rceil$ tests.

The optimal choice of the parameter w gives the procedure with total number of tests equals $2\log_2 t(1 + o(1))$.

References

- [1] Du D.Z., Hwang F.K., Combinatorial Group Testing and Its Applications, 2nd ed., Series on Applied Mathematics, vol. 12, 2000.
- [2] Damaschke P., Sheikh Muhammad A., Triesch E., Two new perspectives on multi-stage group testing, Algorithmica, vol. 67, no. 3, pp. 324-354, 2013.
- M?zard M., Toninelli, C., Group testing with random pools: Optimal two-stage algorithms, *Information Theory*, *IEEE Transactions on*, vol. 57, no. 3, pp. 1736-1745, (2011).
- [4] D'yachkov A.G., Rykov V.V., Bounds on the Length of Disjunctive Codes, // Problems of Information Transmission, vol. 18. no 3. pp. 166-171, 1982.
- [5] D'yachkov A.G., Vorobyev I.V., Polyanskii N.A., Shchukin V.Yu., Bounds on the Rate of Disjunctive Codes, Problems of Information Transmission, vol. 50, no. 1, pp. 27-56, 2014.
- [6] Rashad A.M., Random Coding Bounds on the Rate for List-Decoding Superimposed Codes. Problems of Control and Inform. Theory., vol. 19, no 2, pp. 141-149, 1990.
- [7] D'yachkov A.G., Lectures on Designing Screening Experiments, Lecture Note Series 10, Combinatorial and Computational Mathematics Center, Pohang University of Science and Technology (POSTECH), Korea Republic, Feb. 2003, (survey, 112 pages).
- [8] De Bonis A., Gasieniec L., Vaccaro U., Optimal two-stage algorithms for group testing problems, SIAM J. Comp., vol. 34, no. 5 pp. 1253-1270, 2005.
- [9] Damaschke P., Sheikh Muhammad A., Wiener G. Strict group testing and the set basis problem. Journal of Combinatorial Theory, Series A, vol. 126, pp. 70-91, August 2014.
- [10] Macula A.J., Reuter G.R., Simplified searching for two defects, Journal of statistical planning and inference, vol. 66, no. 1, pp 77-82, 1998.
- [11] Deppe C., Lebedev V.S., Group testing problem with two defects, Problems of Information Transmission, vol. 49, no. 4, pp. 375-381, 2013.